



**SEMiX® 5**

## 3-Level NPC IGBT-Module

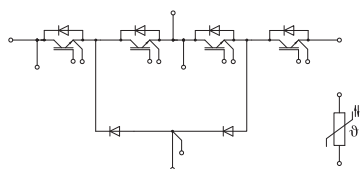
### SEMiX405MLI07E4

#### Features

- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

#### Remarks\*

- Case temperature limited to  $T_c=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_{jop}=150^\circ\text{C}$
- IGBT1 : outer IGBTs T1 & T4
- IGBT2 : inner IGBTs T2 & T3
- Diode1 : outer diodes D1 & D4
- Diode2 : inner diodes D2 & D3
- Diode5 : clamping diodes D5 & D6
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



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Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
<b>IGBT1</b>			
$V_{CES}$	$T_j = 25^\circ\text{C}$	650	V
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	474
		$T_c = 80^\circ\text{C}$	357
$I_{Cnom}$		400	A
$I_{CRM}$	$I_{CRM} = 3 \times I_{Cnom}$	1200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 360\text{ V}, V_{GE} \leq 15\text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 650\text{ V}$	10	$\mu\text{s}$
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>IGBT2</b>			
$V_{CES}$	$T_j = 25^\circ\text{C}$	650	V
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	453
		$T_c = 80^\circ\text{C}$	340
$I_{Cnom}$		400	A
$I_{CRM}$	$I_{CRM} = 3 \times I_{Cnom}$	1200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 360\text{ V}, V_{GE} \leq 15\text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 650\text{ V}$	10	$\mu\text{s}$
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Diode1</b>			
$V_{RRM}$	$T_j = 25^\circ\text{C}$	650	V
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	377
		$T_c = 80^\circ\text{C}$	276
$I_{Fnom}$		300	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	600	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	2160	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Diode2</b>			
$V_{RRM}$	$T_j = 25^\circ\text{C}$	650	V
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	345
		$T_c = 80^\circ\text{C}$	251
$I_{Fnom}$		300	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	600	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	2160	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Diode5</b>			
$V_{RRM}$	$T_j = 25^\circ\text{C}$	650	V
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	327
		$T_c = 80^\circ\text{C}$	237
$I_{Fnom}$		300	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	600	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	2160	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Module</b>			
$I_t(\text{RMS})$		450	A
$T_{stg}$	module without TIM	-40 ... 125	$^\circ\text{C}$
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$	4000	V



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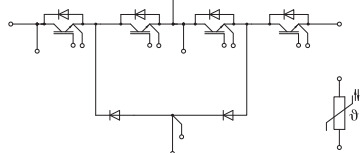
### SEMiX405MLI07E4

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- Diode5 : clamping diodes D5 & D6
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MLI

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT1</b>						
$V_{CE(sat)}$	$I_C = 400\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^{\circ}\text{C}$		1.55	1.95	V
		$T_j = 150^{\circ}\text{C}$		1.75	2.15	V
$V_{CE0}$	chipllevel	$T_j = 25^{\circ}\text{C}$		0.90	1.00	V
		$T_j = 150^{\circ}\text{C}$		0.82	0.90	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^{\circ}\text{C}$		1.63	2.4	m $\Omega$
		$T_j = 150^{\circ}\text{C}$		2.3	3.1	m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 8\text{ mA}$		5.1	5.8	6.4	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^{\circ}\text{C}$				0.4	mA
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		24.7		nF
$C_{oes}$		$f = 1\text{ MHz}$		1.54		nF
$C_{res}$		$f = 1\text{ MHz}$		0.73		nF
$Q_G$	$V_{GE} = -15\text{V}...+15\text{V}$			3930		nC
$R_{Gint}$	$T_j = 25^{\circ}\text{C}$			1.0		$\Omega$
$t_{d(on)}$	$V_{CC} = 300\text{ V}$	$T_j = 150^{\circ}\text{C}$		145		ns
$t_r$	$I_C = 400\text{ A}$	$T_j = 150^{\circ}\text{C}$		89		ns
$E_{on}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^{\circ}\text{C}$		5.3		mJ
$t_{d(off)}$	$R_{G on} = 2\ \Omega$	$T_j = 150^{\circ}\text{C}$		414		ns
$t_f$	$R_{G off} = 1.6\ \Omega$	$T_j = 150^{\circ}\text{C}$		100		ns
$E_{off}$	$di/dt_{on} = 4750\text{ A}/\mu\text{s}$ $di/dt_{off} = 3300\text{ A}/\mu\text{s}$	$T_j = 150^{\circ}\text{C}$		20.2		mJ
		$T_j = 150^{\circ}\text{C}$				
$R_{th(j-c)}$	per IGBT				0.13	K/W
$R_{th(c-s)}$	per IGBT ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^{\circ}\text{K})$ )			0.04		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			0.03		K/W
<b>IGBT2</b>						
$V_{CE(sat)}$	$I_C = 400\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^{\circ}\text{C}$		1.55	1.95	V
		$T_j = 150^{\circ}\text{C}$		1.75	2.15	V
$V_{CE0}$	chipllevel	$T_j = 25^{\circ}\text{C}$		0.90	1.00	V
		$T_j = 150^{\circ}\text{C}$		0.82	0.90	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^{\circ}\text{C}$		1.63	2.4	m $\Omega$
		$T_j = 150^{\circ}\text{C}$		2.3	3.1	m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 8\text{ mA}$		5.1	5.8	6.4	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^{\circ}\text{C}$				0.4	mA
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		24.7		nF
$C_{oes}$		$f = 1\text{ MHz}$		1.54		nF
$C_{res}$		$f = 1\text{ MHz}$		0.73		nF
$Q_G$	$V_{GE} = -15\text{V}...+15\text{V}$			3930		nC
$R_{Gint}$	$T_j = 25^{\circ}\text{C}$			1.0		$\Omega$
$t_{d(on)}$	$V_{CC} = 300\text{ V}$	$T_j = 150^{\circ}\text{C}$		114.6		ns
$t_r$	$I_C = 400\text{ A}$	$T_j = 150^{\circ}\text{C}$		88.4		ns
$E_{on}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^{\circ}\text{C}$		6		mJ
$t_{d(off)}$	$R_{G on} = 2\ \Omega$	$T_j = 150^{\circ}\text{C}$		412.6		ns
$t_f$	$R_{G off} = 1.6\ \Omega$	$T_j = 150^{\circ}\text{C}$		121.6		ns
$E_{off}$	$di/dt_{on} = 4750\text{ A}/\mu\text{s}$ $di/dt_{off} = 3300\text{ A}/\mu\text{s}$	$T_j = 150^{\circ}\text{C}$		18.7		mJ
		$T_j = 150^{\circ}\text{C}$				
$R_{th(j-c)}$	per IGBT				0.14	K/W
$R_{th(c-s)}$	per IGBT ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^{\circ}\text{K})$ )			0.045		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			0.026		K/W



## SEMiX® 5

### 3-Level NPC IGBT-Module

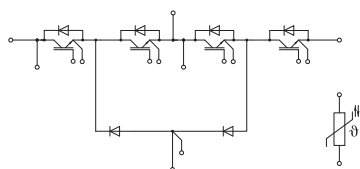
#### SEMiX405MLI07E4

#### Features

- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

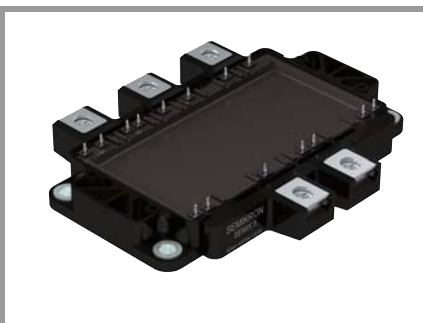
#### Remarks\*

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_{jop}=150^\circ\text{C}$
- IGBT1 : outer IGBTs T1 & T4
- IGBT2 : inner IGBTs T2 & T3
- Diode1 : outer diodes D1 & D4
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- Diode5 : clamping diodes D5 & D6
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Diode1</b>						
$V_F = V_{EC}$	$I_F = 300\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.40	1.76		V
		$T_j = 150^\circ\text{C}$	1.39	1.77		V
$V_{F0}$	chipelevel	$T_j = 25^\circ\text{C}$	1.04	1.24		V
		$T_j = 150^\circ\text{C}$	0.85	0.99		V
$r_F$	chipelevel	$T_j = 25^\circ\text{C}$	1.19	1.76		mΩ
		$T_j = 150^\circ\text{C}$	1.79	2.6		mΩ
$I_{RRM}$	$I_F = 400\text{ A}$	$T_j = 150^\circ\text{C}$	212			A
$Q_{rr}$	$di/dt_{off} = 4750\text{ A}/\mu\text{s}$ $V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$	21.63			μC
$E_{rr}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	10.9			mJ
$R_{th(j-c)}$	per diode				0.21	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$ )			0.038		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			0.034		K/W
<b>Diode2</b>						
$V_F = V_{EC}$	$I_F = 300\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.40	1.76		V
		$T_j = 150^\circ\text{C}$	1.39	1.77		V
$V_{F0}$	chipelevel	$T_j = 25^\circ\text{C}$	1.04	1.24		V
		$T_j = 150^\circ\text{C}$	0.85	0.99		V
$r_F$	chipelevel	$T_j = 25^\circ\text{C}$	1.19	1.76		mΩ
		$T_j = 150^\circ\text{C}$	1.79	2.6		mΩ
$I_{RRM}$	$I_F = 400\text{ A}$	$T_j = 150^\circ\text{C}$	212			A
$Q_{rr}$	$di/dt_{off} = 4750\text{ A}/\mu\text{s}$ $V_R = 300\text{ V}$	$T_j = 150^\circ\text{C}$	4			μC
$E_{rr}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	-			mJ
$R_{th(j-c)}$	per diode				0.24	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$ )			0.038		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			0.03		K/W
<b>Diode5</b>						
$V_F = V_{EC}$	$I_F = 300\text{ A}$ chipelevel	$T_j = 25^\circ\text{C}$	1.40	1.76		V
		$T_j = 150^\circ\text{C}$	1.39	1.77		V
$V_{F0}$	chipelevel	$T_j = 25^\circ\text{C}$	1.04	1.24		V
		$T_j = 150^\circ\text{C}$	0.85	0.99		V
$r_F$	chipelevel	$T_j = 25^\circ\text{C}$	1.19	1.76		mΩ
		$T_j = 150^\circ\text{C}$	1.79	2.6		mΩ
$I_{RRM}$	$I_F = 400\text{ A}$	$T_j = 150^\circ\text{C}$	309			A
$Q_{rr}$	$di/dt_{off} = 4750\text{ A}/\mu\text{s}$ $V_R = 300\text{ V}$	$T_j = 150^\circ\text{C}$	40			μC
$E_{rr}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	6.1			mJ
$R_{th(j-c)}$	per diode				0.26	K/W
$R_{th(c-s)}$	per diode ( $\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$ )			0.047		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			0.037		K/W



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## 3-Level NPC IGBT-Module

### SEMiX405MLI07E4

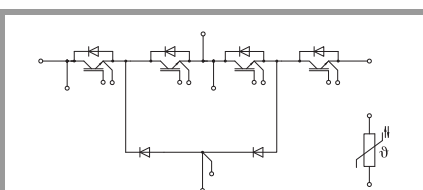
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Module</b>						
$L_{sCE1}$				27		nH
$L_{sCE2}$				34		nH
$R_{CC'+EE'}$	measured between terminal 5 and 1	$T_C = 25^\circ\text{C}$		0.8		m $\Omega$
		$T_C = 125^\circ\text{C}$		1.1		m $\Omega$
$R_{th(c-s)1}$	calculated without thermal coupling			0.004		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module ( $\lambda_{grease}=0.81\text{ W/(m}^2\text{K)}$ )			0.007		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module, pre-applied phase change material			0.005		K/W
$M_s$	to heat sink (M5)		3		6	Nm
$M_t$		to terminals (M6)	3		6	Nm
						Nm
$W$				398		g
<b>Temperature Sensor</b>						
$R_{100}$	$T_C=100^\circ\text{C}$ ( $R_{25}=5\text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; $T[\text{K}]$ ;			$3550 \pm 2\%$		K



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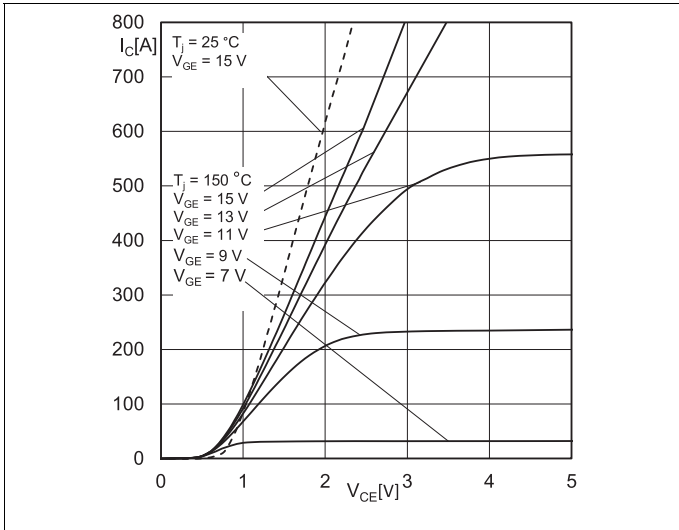


Fig. 1: Typ. IGBT1 output characteristic, incl.  $R_{CC'+EE'}$

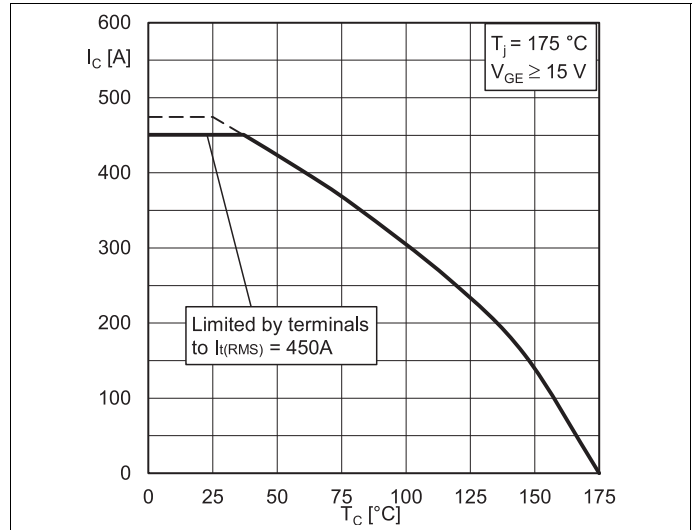


Fig. 2: IGBT1 rated current vs. Temperature  $I_C=f(T_C)$

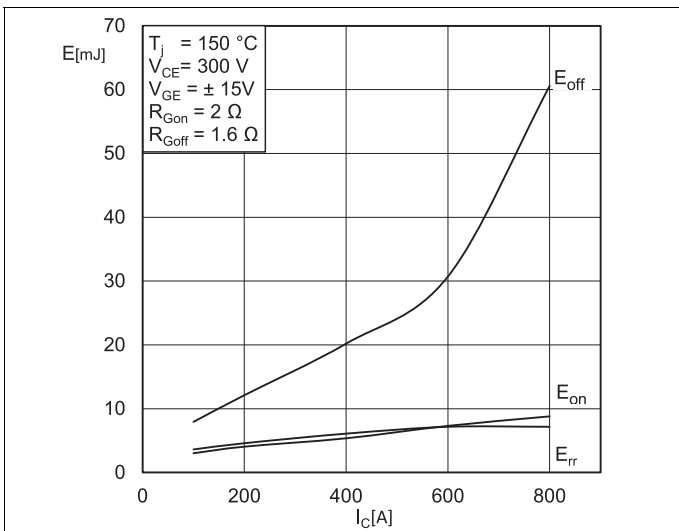


Fig. 3: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(I_C)$

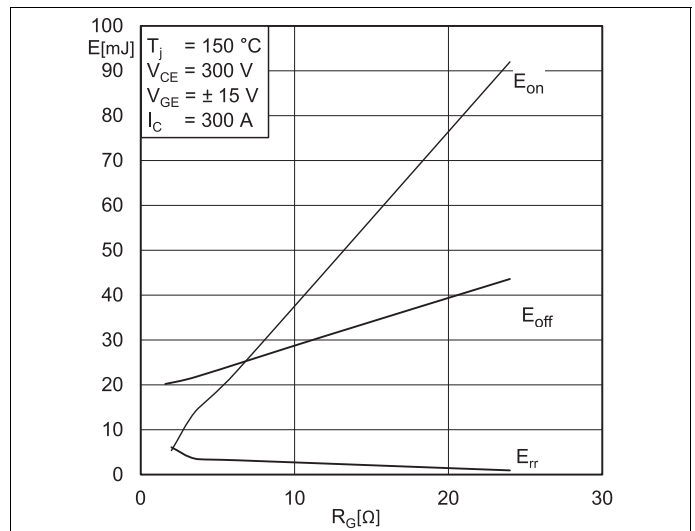


Fig. 4: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(R_G)$

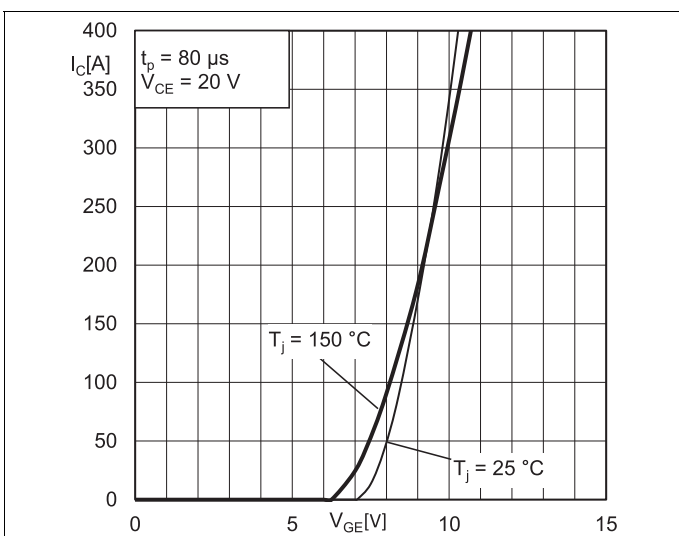


Fig. 5: Typ. IGBT1 transfer characteristic

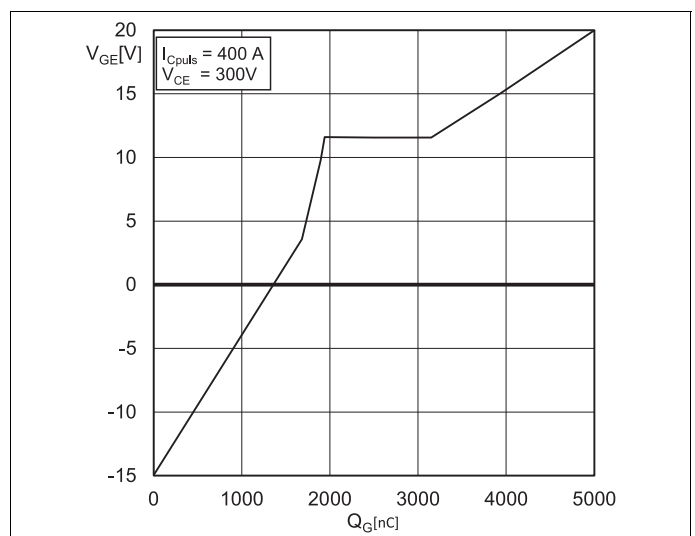


Fig. 6: Typ. IGBT1 gate charge characteristic

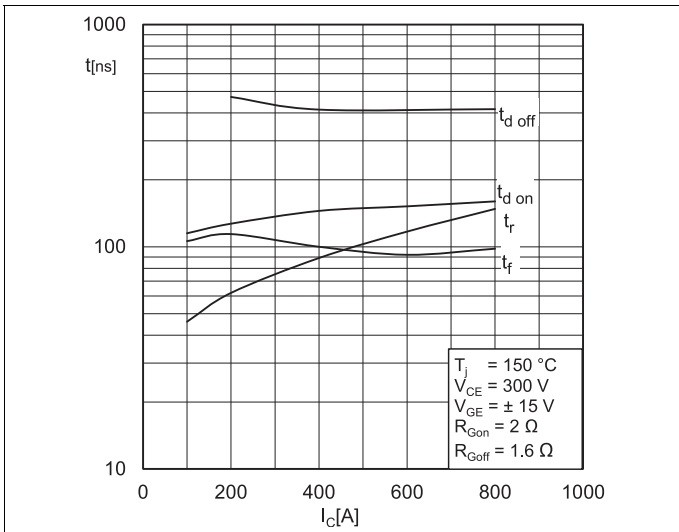


Fig. 7: Typ. IGBT1 switching times vs.  $I_c$

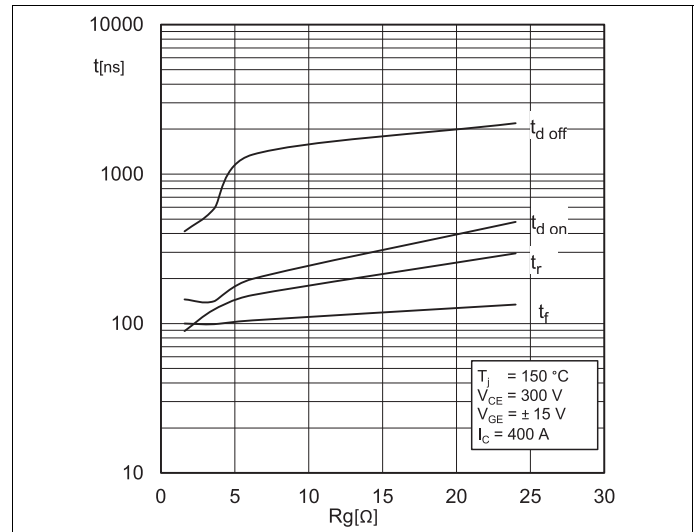


Fig. 8: Typ. IGBT1 switching times vs. gate resistor  $R_g$

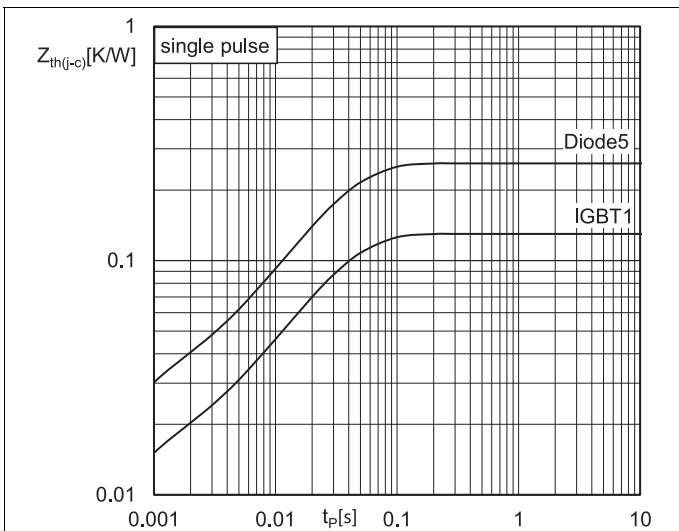


Fig. 9: Transient thermal impedance of IGBT1 & Diode5

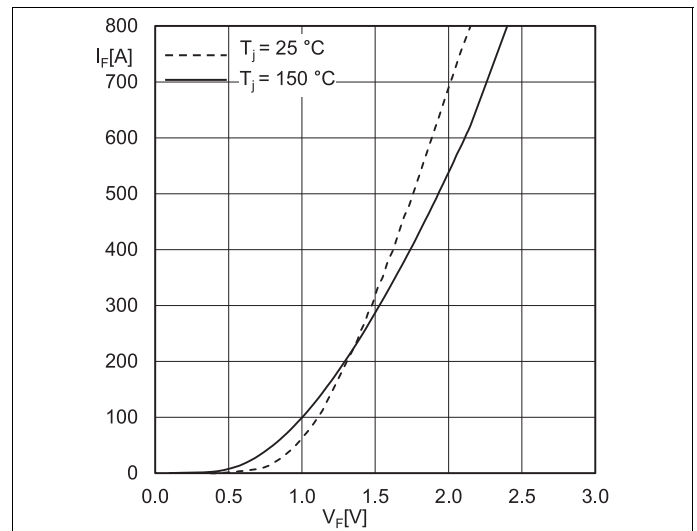


Fig. 10: Typ. Diode5 forward characteristic, incl.  $R_{CC+EE'}$

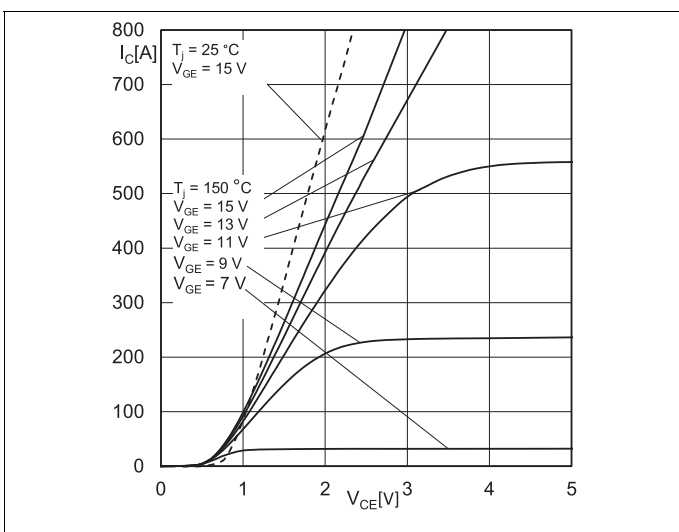


Fig. 13: Typ. IGBT2 output characteristic, incl.  $R_{CC+EE'}$

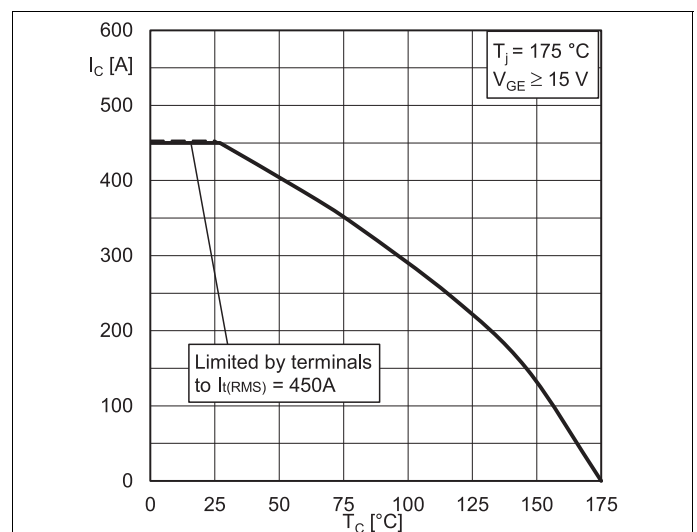


Fig. 14: IGBT2 Rated current vs. Temperature  $I_c = f(T_c)$

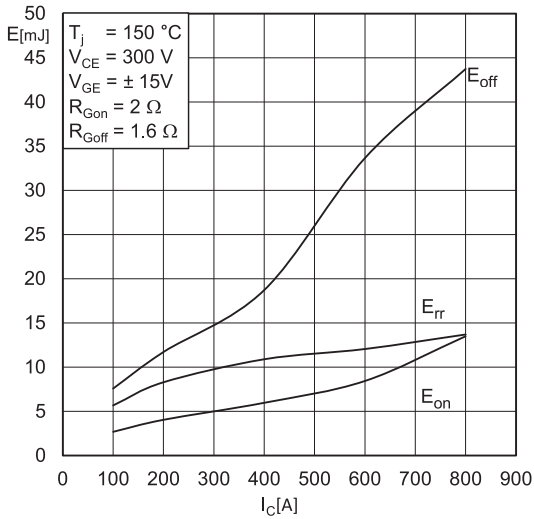


Fig. 15: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(I_C)$

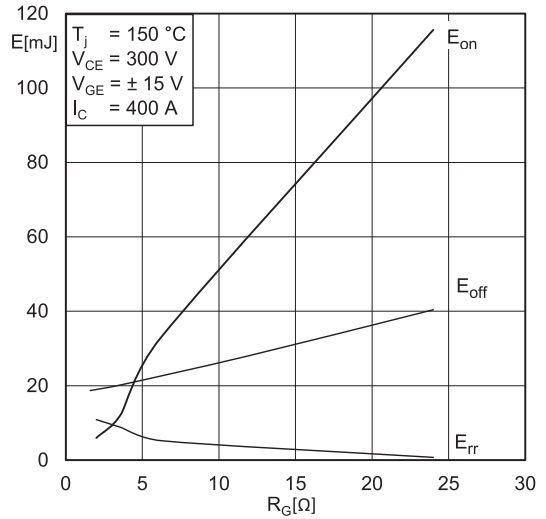


Fig. 16: Typ. IGBT2 & Diode1 turn-on / -off energy =  $f(R_G)$

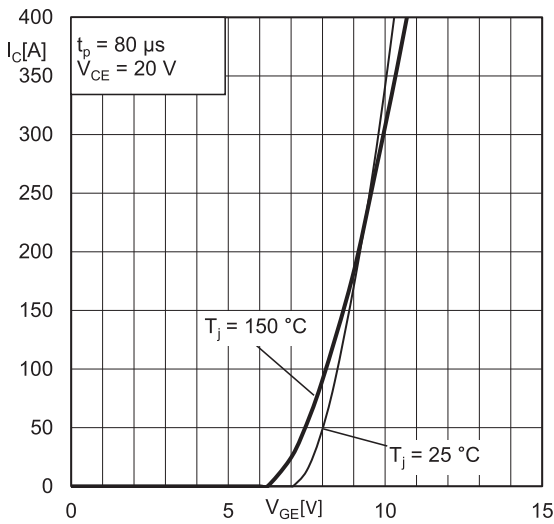


Fig. 17: Typ. IGBT2 transfer characteristic

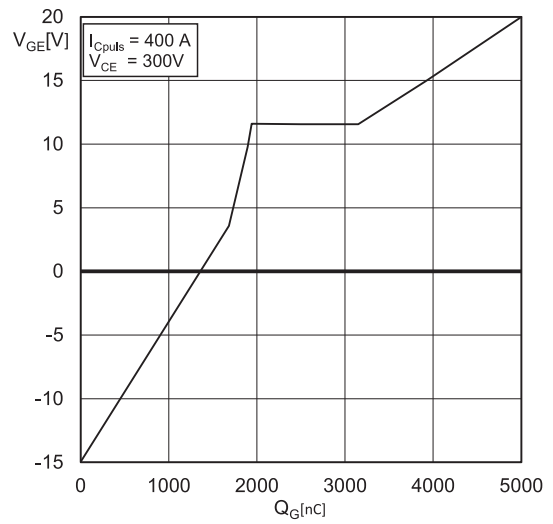


Fig. 18: Typ. IGBT2 gate charge characteristic

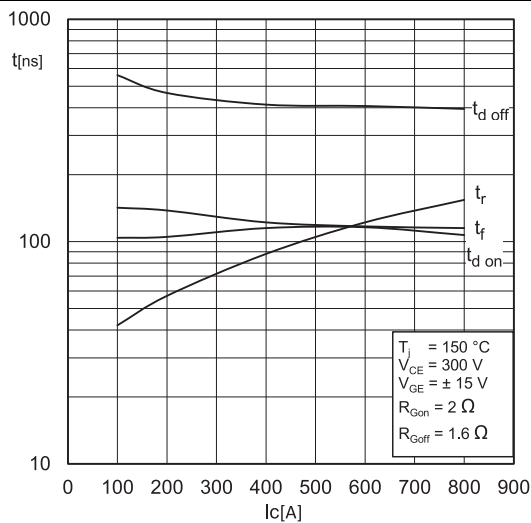


Fig. 19: Typ. IGBT2 switching times vs.  $I_C$

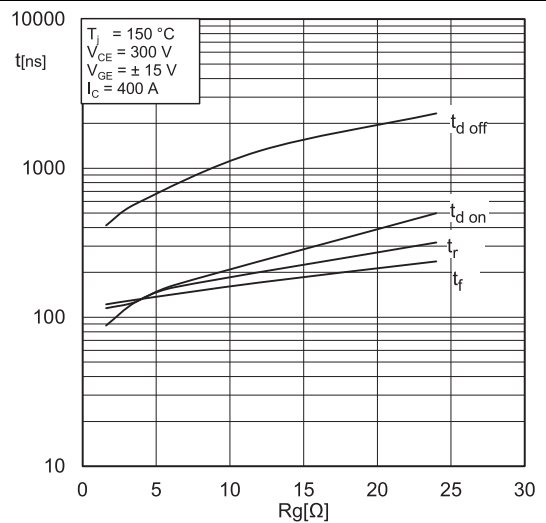


Fig. 20: Typ. IGBT2 switching times vs. gate resistor  $R_G$

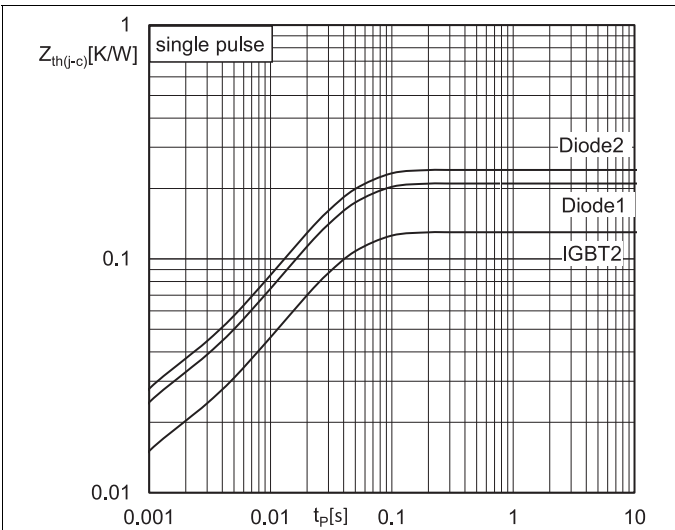


Fig. 21: Transient thermal impedance of IGBT2, Diode1 & Diode2

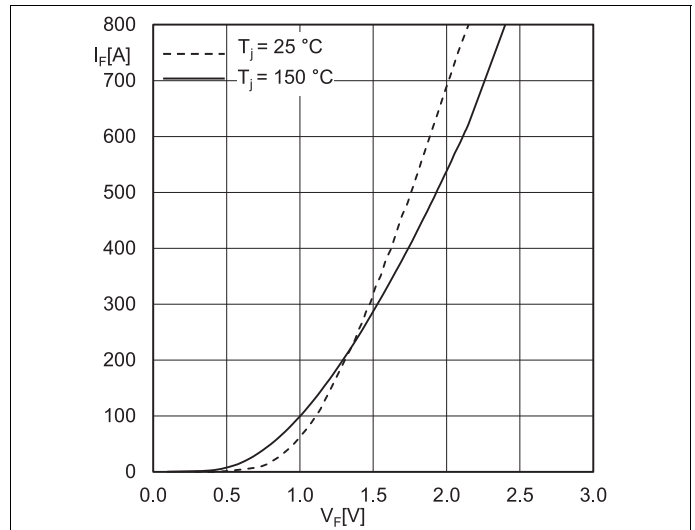
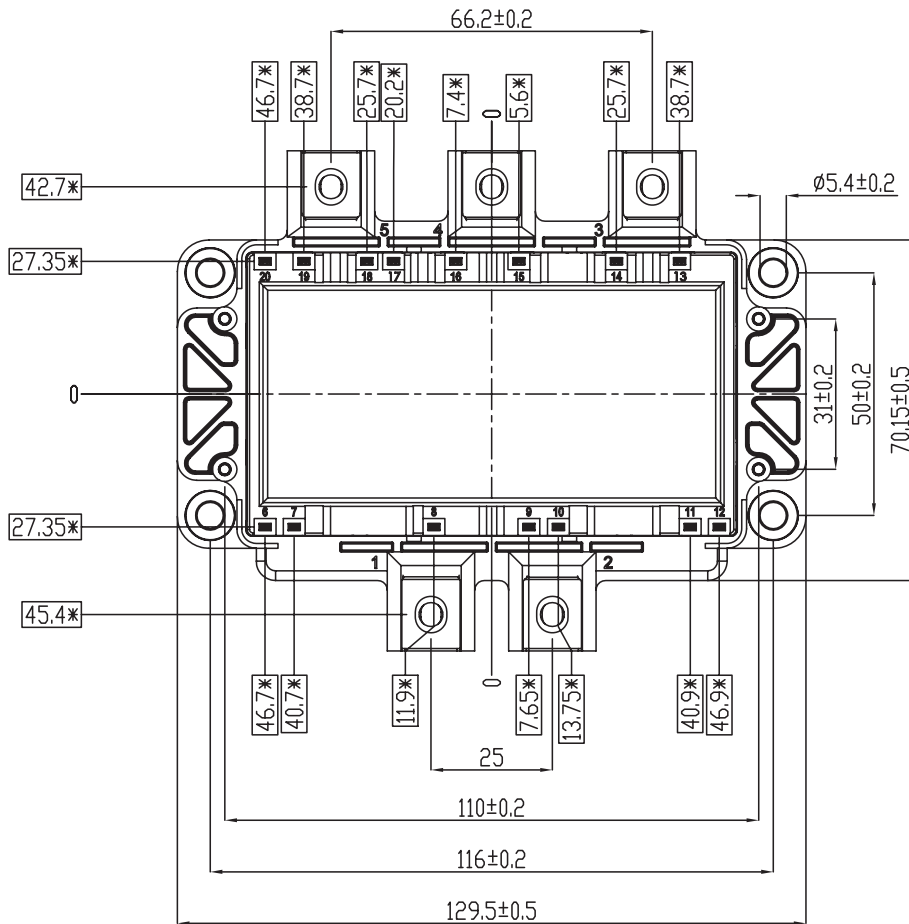
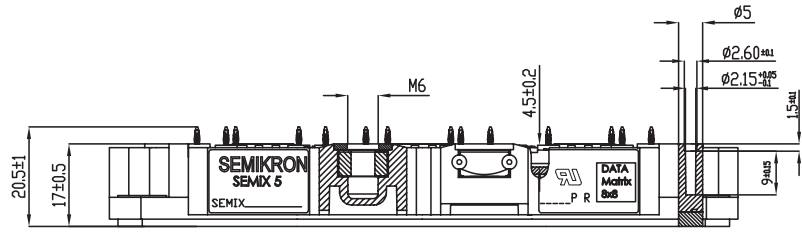


Fig. 22: Typ. Diode1 & Diode2 forward characteristic, incl.  $R_{CC+EE}$



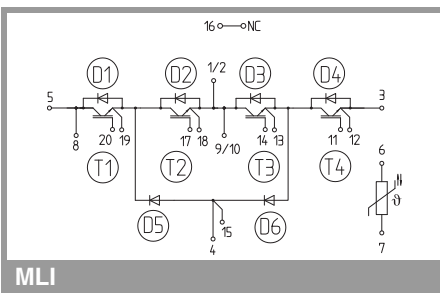
# SEMiX405MLI07E4



\* = All dimension with tolerance of  $\begin{matrix} \oplus \\ \ominus \end{matrix} \ 0.4$

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



MLI

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

## **\*IMPORTANT INFORMATION AND WARNINGS**

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